

Notice of References Cited	Application/Control No. 10/717,131	Applicant(s)/Patent Under Reexamination ONISHI ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-53812-A1	02-2000	Japan	Kenji et al	C08L 23/02
	O	EP-1043361-A1	11-2000	Japan EPX	Onishi et al	C08L 29/04
	P					
	Q					
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NON-PATENT DOCUMENTS

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